

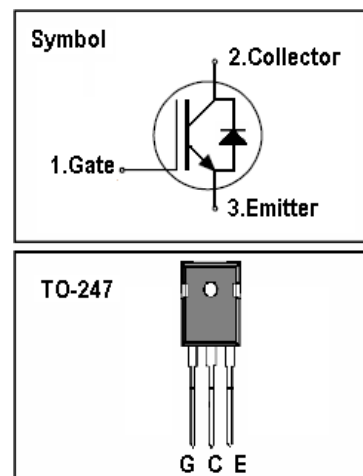
## IGBT

### Features

- 1200V,25A
- $V_{CE(sat)}(typ.)=2.2V@V_{GE}=15V,I_C=25A$
- High speed switching
- Higher system efficiency
- Soft current turn-off waveforms
- Square RBSOA using NPT technology

### General Description

KEDA NPT IGBTs offer lower losses and higher energy efficiency for application such as IH (induction heating), UPS, general inverter and other soft switching applications.



### Absolute Maximum Ratings

Symbol	Parameter	Value	Units
$V_{CES}$	Collector-Emitter Voltage	1200	V
$V_{GES}$	Gate-Emitter Voltage	$\pm 30$	V
$I_C$	Continuous Collector Current ( $T_C=25^{\circ}C$ )	50	A
	Continuous Collector Current ( $T_C=100^{\circ}C$ )	25	A
$I_{CM}$	Pulsed Collector Current (Note 1)	120	A
$I_F$	Diode Continuous Forward Current ( $T_C=100^{\circ}C$ )	25	A
$I_{FM}$	Diode Maximum Forward Current (Note 1)	120	A
$t_{sc}$	Short Circuit Withstand Time	10	us
$P_D$	Maximum Power Dissipation ( $T_C=25^{\circ}C$ )	202	W
	Maximum Power Dissipation ( $T_C=100^{\circ}C$ )	79	W
$T_J$	Operating Junction Temperature Range	-55 to +150	$^{\circ}C$
$T_{STG}$	Storage Temperature Range	-55 to +150	$^{\circ}C$

### Thermal Characteristics

Symbol	Parameter	Max.	Units
$R_{th\ j-c}$	Thermal Resistance, Junction to case for IGBT	0.45	$^{\circ}C/W$
$R_{th\ j-c}$	Thermal Resistance, Junction to case for Diode	0.85	$^{\circ}C/W$
$R_{th\ j-a}$	Thermal Resistance, Junction to Ambient	40	$^{\circ}C/W$

## Electrical Characteristics (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
BV <sub>CES</sub>	Collector-Emitter Breakdown Voltage	V <sub>GE</sub> = 0V, I <sub>C</sub> = 250uA	1200	-	-	V
I <sub>CES</sub>	Collector-Emitter Leakage Current	V <sub>CE</sub> = 1200V, V <sub>GE</sub> = 0V	-	-	250	uA
I <sub>GES</sub>	Gate Leakage Current, Forward	V <sub>GE</sub> =30V, V <sub>CE</sub> = 0V	-	-	100	nA
	Gate Leakage Current, Reverse	V <sub>GE</sub> = -30V, V <sub>CE</sub> = 0V	-	-	-100	nA
V <sub>GE(th)</sub>	Gate Threshold Voltage	V <sub>GE</sub> = V <sub>CE</sub> , I <sub>C</sub> = 250uA	4.5	-	5.5	V
V <sub>CE(sat)</sub>	Collector-Emitter Saturation Voltage	V <sub>GE</sub> =15V, I <sub>C</sub> = 25A	-	2.2	-	V
Q <sub>g</sub>	Total Gate Charge	V <sub>CC</sub> =960V V <sub>GE</sub> =15V I <sub>C</sub> =25A	-	125	-	nC
Q <sub>ge</sub>	Gate-Emitter Charge		-	33	-	nC
Q <sub>gc</sub>	Gate-Collector Charge		-	64	-	nC
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>CC</sub> =600V V <sub>GE</sub> =15V I <sub>C</sub> =25A R <sub>G</sub> =28Ω Inductive Load T <sub>C</sub> =25 °C	-	42	-	ns
t <sub>r</sub>	Turn-on Rise Time		-	53	-	ns
t <sub>d(off)</sub>	Turn-off Delay Time		-	460	-	ns
t <sub>f</sub>	Turn-off Fall Time		-	106	-	ns
E <sub>on</sub>	Turn-on Switching Loss		-	1.6	-	mJ
E <sub>off</sub>	Turn-off Switching Loss		-	1.3	-	mJ
E <sub>ts</sub>	Total Switching Loss		-	2.8	-	mJ
C <sub>ies</sub>	Input Capacitance	V <sub>CE</sub> =25V V <sub>GE</sub> =0V f = 100kHz	-	560	-	pF
C <sub>oes</sub>	Output Capacitance		-	145	-	pF
C <sub>res</sub>	Reverse Transfer Capacitance		-	81	-	pF
R <sub>Gint</sub>	Integrated gate resistor		-	2.0	-	Ω

## Electrical Characteristics of Diode (T<sub>C</sub>=25°C unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> =25A	1.9	2.3	2.7	V
t <sub>rr</sub>	Diode Reverse Recovery Time	V <sub>CE</sub> = 600V I <sub>F</sub> = 25A dI <sub>F</sub> /dt = 500A/us	-	150		ns
I <sub>rr</sub>	Diode peak Reverse Recovery Current		-	18		A
Q <sub>rr</sub>	Diode Reverse Recovery Charge		-	1350		nC

### Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature

## Typical Performance Characteristics

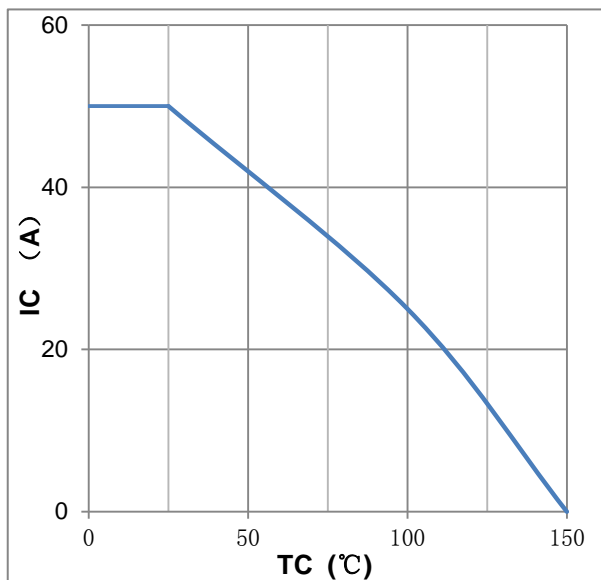


Figure1: maximum DC collector current  
VS. case temperature

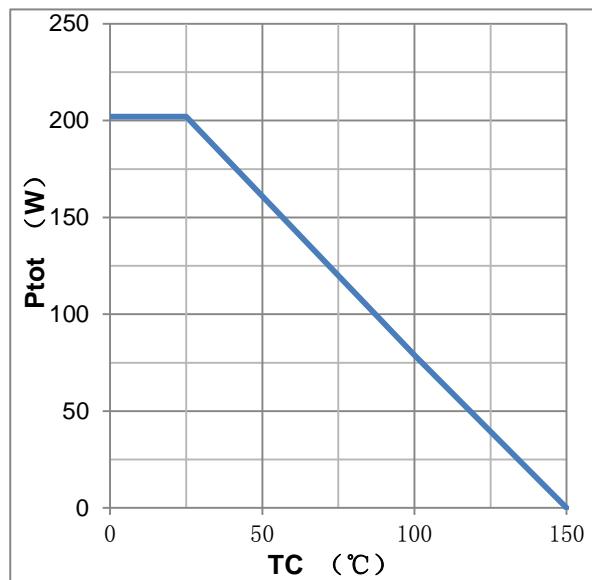


Figure2: power dissipation VS. case temperature

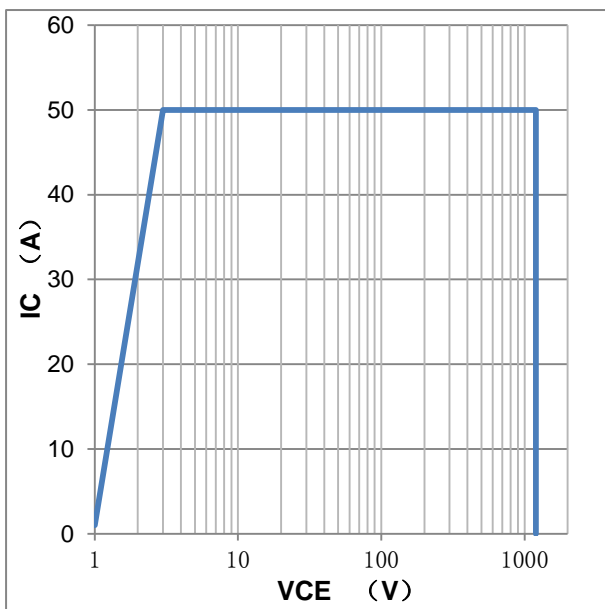


Figure3: reverse bias SOA,  $T_J = 150^{\circ}\text{C}$ ,  $V_{GE} = 15\text{V}$

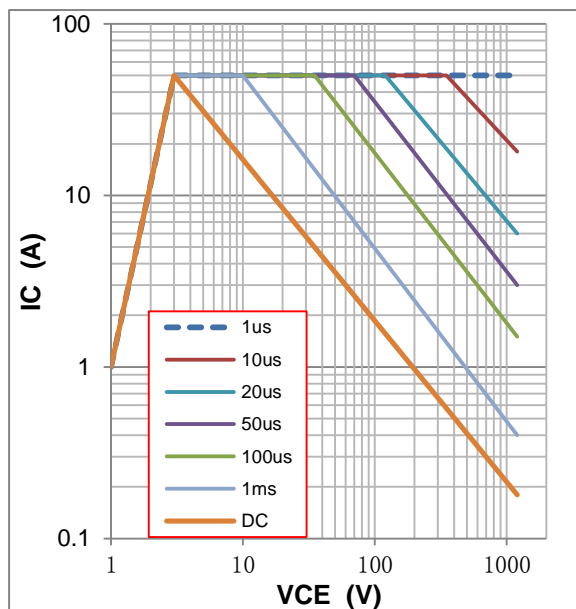


Figure4: forward SOA,  $T_C = 25^{\circ}\text{C}$ ,  $T_J \leq 150^{\circ}\text{C}$

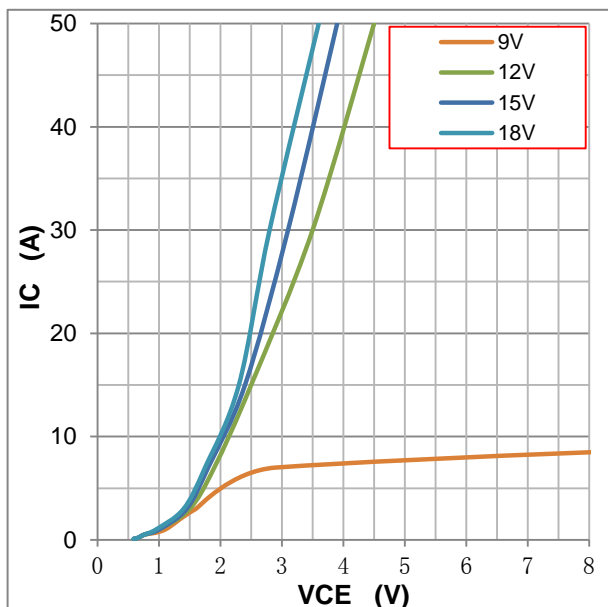


Figure5:typical IGBT output characteristics,  
 $T_J=25^{\circ}\text{C}$ ;  $t_p=300\mu\text{s}$

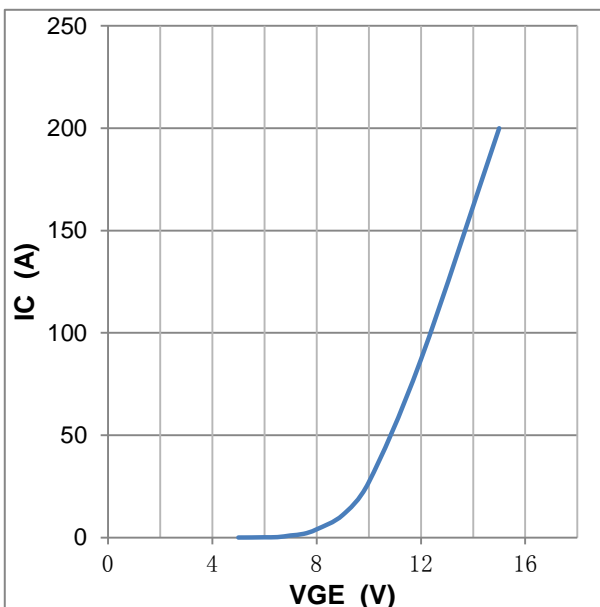


Figure6:typical trans characteristics,  $V_{CE}=20\text{V}$ ,  $t_p=20\mu\text{s}$

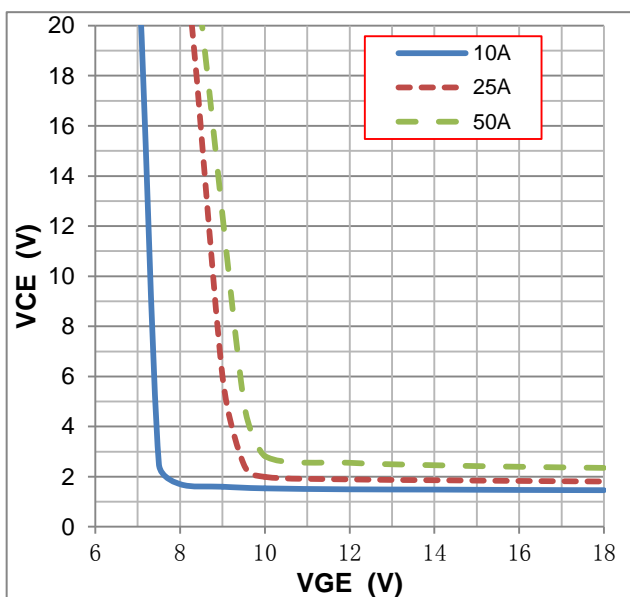


Figure7: typical  $V_{CE}$  VS.  $V_{GE}$ ,  $T_J=25^{\circ}\text{C}$

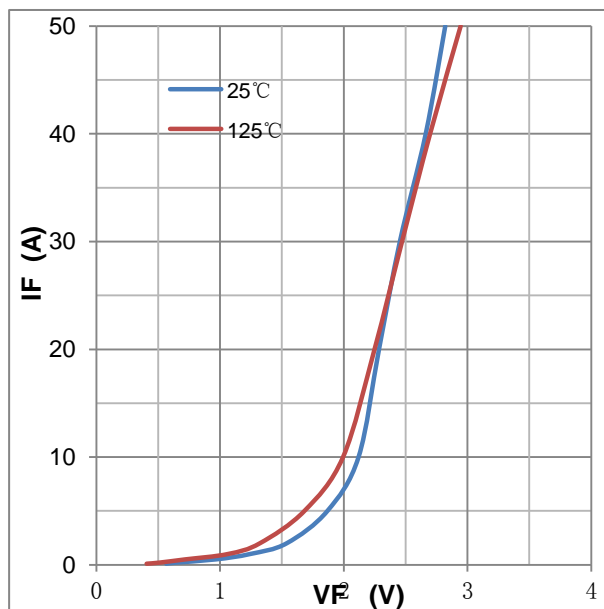


Figure8:typical diode forward characteristic,  $t_p=300\mu\text{s}$

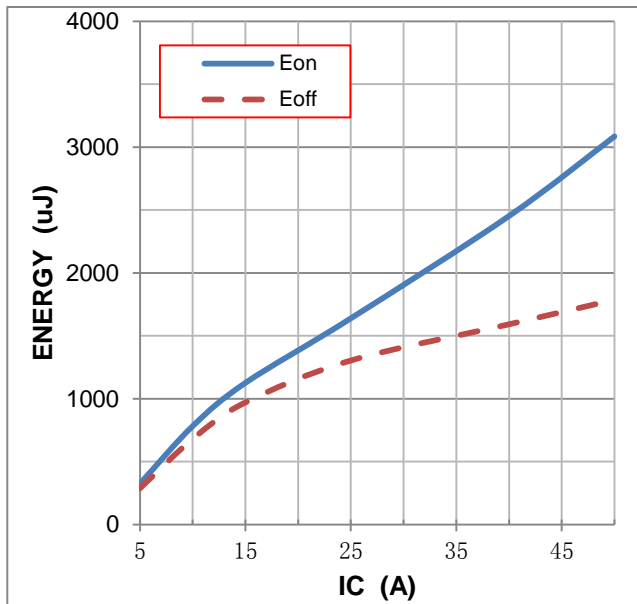


Figure9: typical energy loss VS. IC, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, Rg=28Ω,

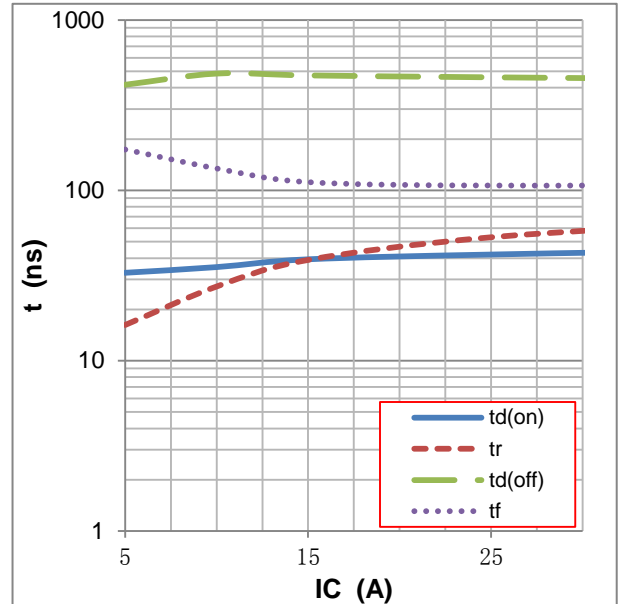


Figure10: typical switching time VS. IC, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, Rg=28Ω,

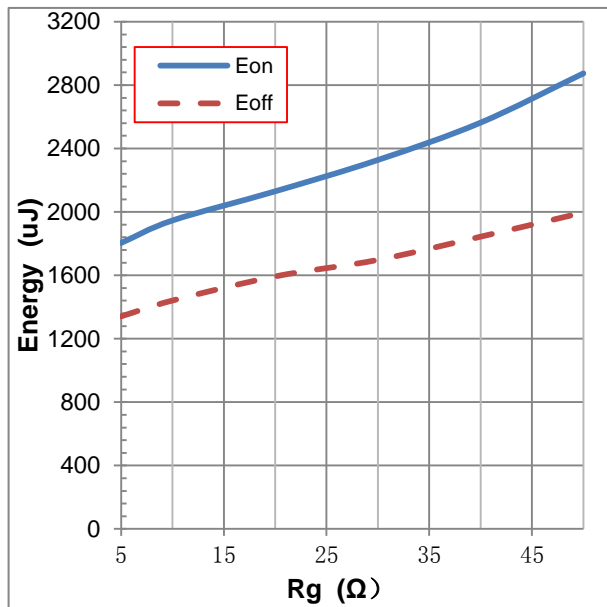


Figure11: typical energy loss VS. Rg, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, IC=25A

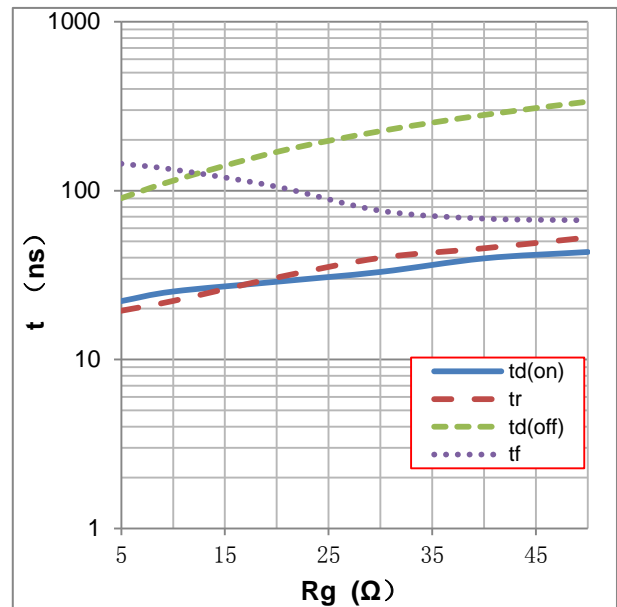


Figure12: typical switching time VS. Rg, TC=25°C,  
L=500uH, VCE=600V, VGE=15V, IC=25A

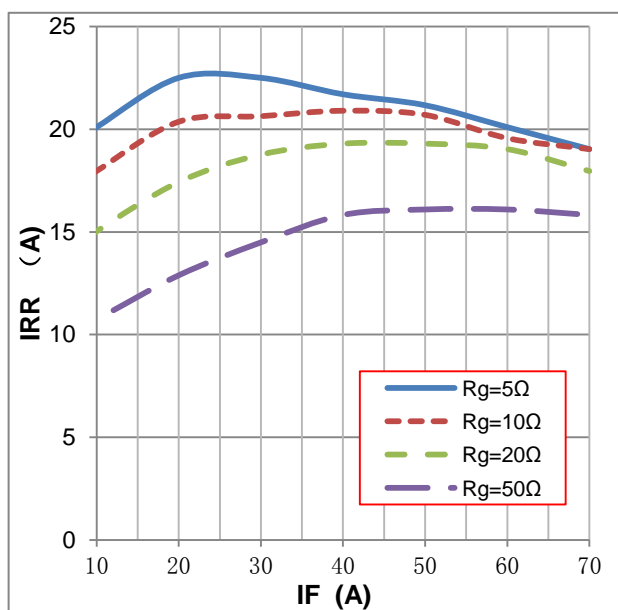


Figure13: typical diode IRR VS. IF, TC=25°C

VCC=600V, VGE=15V

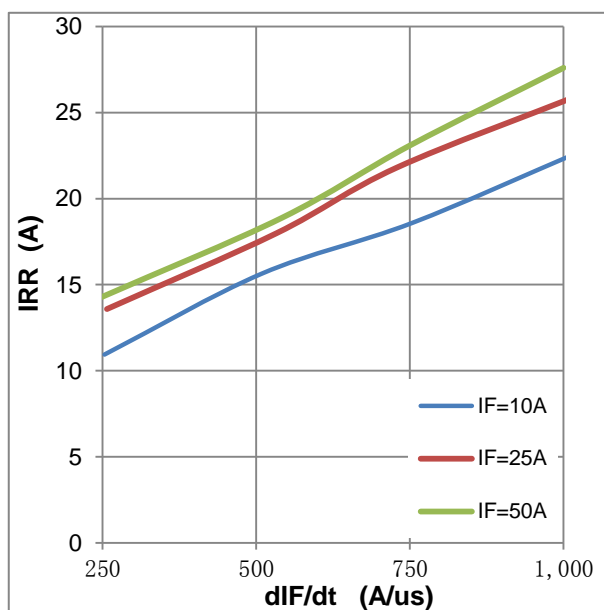


Figure14: typical diode IRR VS. dIF/dt

VCC=600V, VGE=15V

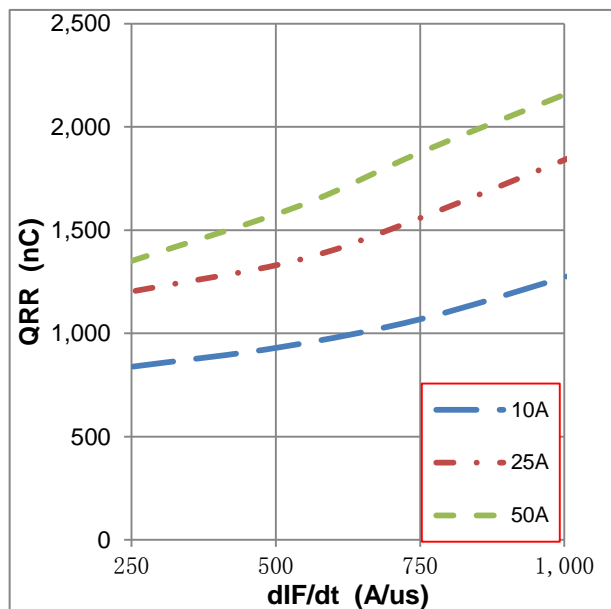


Figure15: typical diode QRR VS. dIF/dt

VCC=600V, VGE=15V

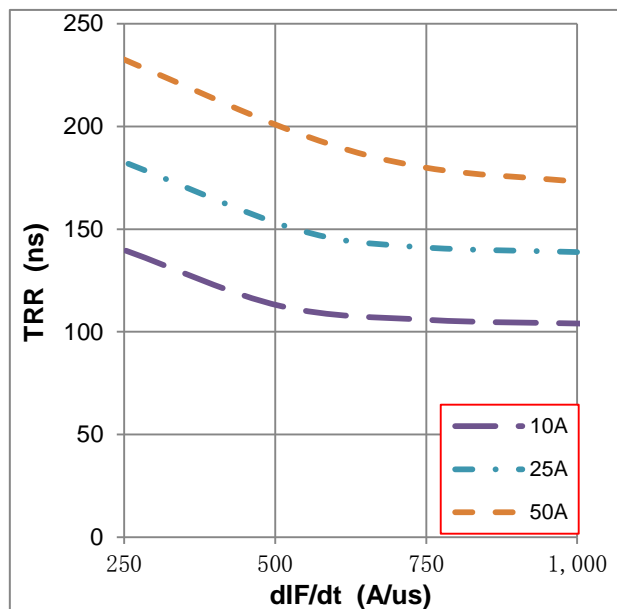


Figure16: typical diode TRR VS. dIF/dt,

VCC=600V, VGE=15V

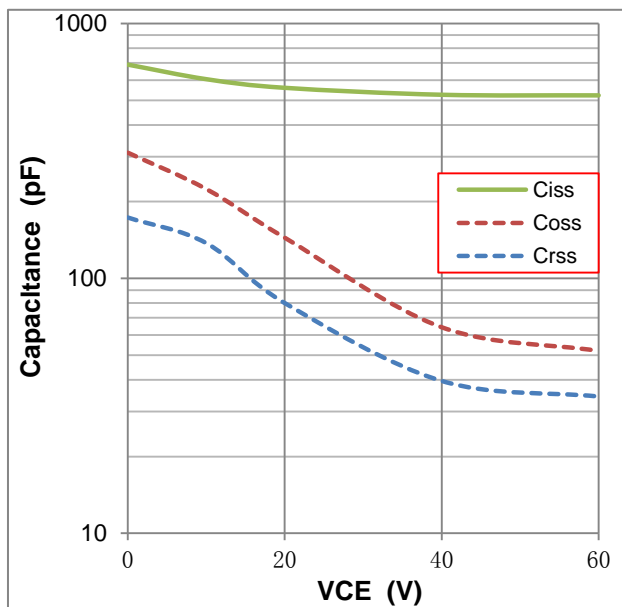


Figure17:typical capacitance VS. VCE,VGE=0V,f=100kHz

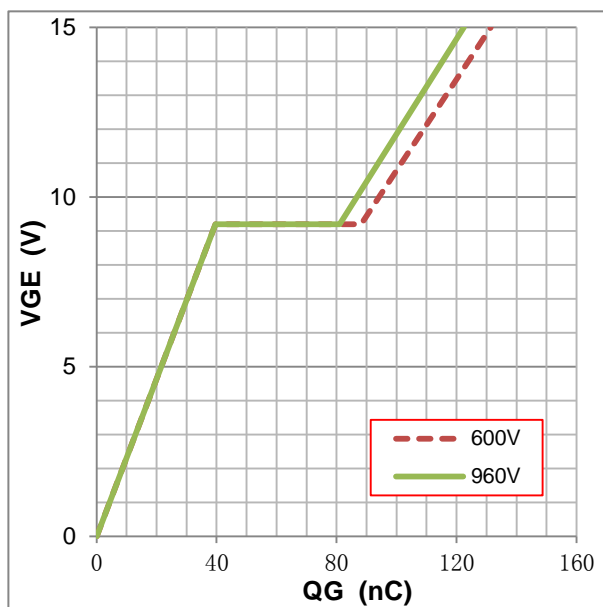


Figure18:typical gate charge VS. VGE,IC=25A

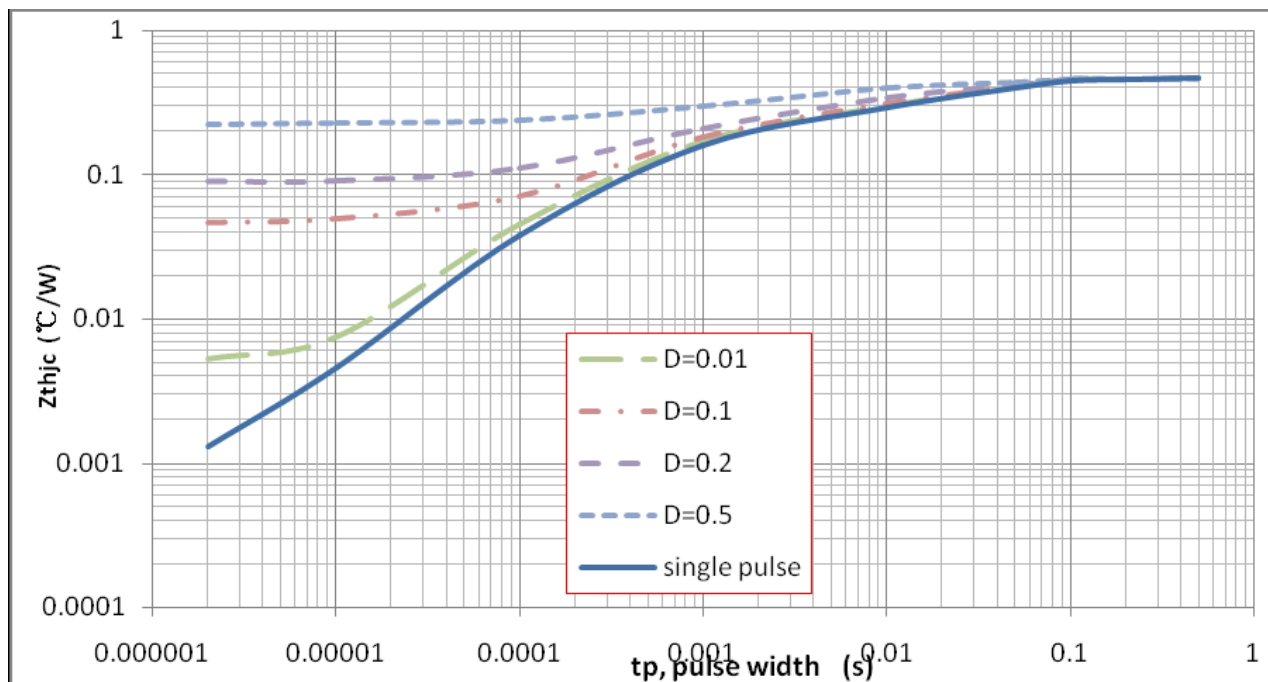
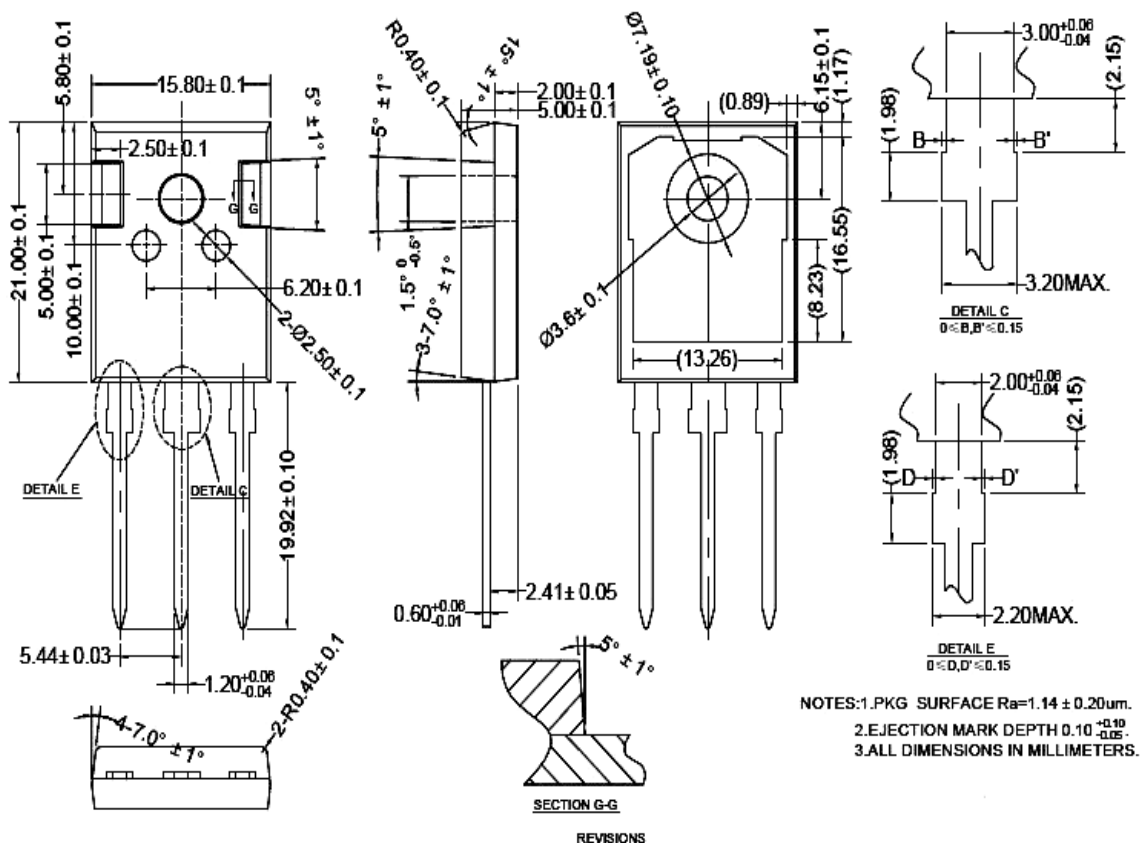


Figure19:normalized transient thermal impedance, junction-to-case

Note1.Duty factor  $D=t_1/t_2$ ;

Note2:peak  $T_J = PDM \times Z_{thjc} + T_C$

## TO247 PACKAGE OUTLINE



公差标注	公差值	表面粗糙度
0	±0.2	Ra3.2~6.3
0.0	±0.1	Ra1.6~3.2
0.00	±0.01	Ra0.8~1.6
0.000	±0.005	Ra0.4~0.8
0.0000	±0.002	Ra0.2~0.4

0≤D,D'≤0.15

NOTES: 1.PKG SURFACE Ra=1.14±0.20um.  
2.EJECTION MARK DEPTH 0.10<sup>+0.10</sup>/<sub>-0.05</sub>.  
3.ALL DIMENSIONS IN MILLIMETERS.